Notes and News

Announcements and other items of crystallographic interest will be published under this heading at the discretion of the Editorial Board. The notes (in duplicate) should be sent to the General Secretary of the International Union of Crystallography (D. W. Smits, Rekencentrum der Rijksuniversiteit, Grote Appelstraat 11, Groningen, The Netherlands). Publication of an item in a particular issue cannot be guaranteed unless the draft is received 8 weeks before the date of publication.

The Training of a Crystallographer

The X-ray Analysis Group of The Institute of Physics and The Physical Society will hold its Spring Conference at the University of Edinburgh on Thursday and Friday, 8 and 9 April 1965. The first day will be devoted to a discussion of the training of crystallographers, with special emphasis on the requirements of industry, and the second day will be devoted to short accounts of current work in structure analysis. Registration forms may be obtained from the Administration Assistant, The Institute of Physics and The Physical Society, 47 Belgrave Square, London, S.W. 1, England. The closing date for receipt of applications is 6 March 1965.

Book Review

Works intended for notice in this column should be sent direct to the Editor (A. J. C. Wilson, Department of Physics, University College, Cathays Park, Cardiff, Great Britain). As far as practicable books will be reviewed in a country different from that of publication.

Theorie et technique de la radiocristallographie. By A. GUINIER. Pp. 740, 345 figs. Paris: A. Dunod, 1964. Price: 124 F.

The third edition of Guinier's well-known and excellent representation of the theory and experimental techniques of X-ray diffraction differs only very little from the second edition, which appeared in 1956, and has already been reviewed (*cf. Acta Cryst.* (1957), **10**, 386). The most important alterations are:

1. New references have been added to the bibliographies of the various chapters, and some others have been replaced by more recent ones. To a minor extent the new literature is briefly discussed in the text.
2. To the chapter dealing with small-angle scattering of X-rays two contributions (2 pages) are added on integrated intensities and difficulties of the interpretation of low-angle scattering (multiple Bragg reflexions and influence of very large particles).
3. The discussion of the Guinier–Preston zones in Chapter XIII (Crystal imperfections) has been replaced by a new version.

Other changes are of minor importance.

The reviewer regrets that the author apparently could not find the time to give a full account of recent developments, especially of disorder and crystal imperfections and small-angle scattering, which deserve to be considered in a publication with the scope and level of Guinier's book. Thus it has lost something of its original timeliness. This need not necessarily be a disadvantage for readers wishing to study the basic principles of X-ray diffraction rather than its recent results.

Some figures already criticized by the reviewer of the second edition have become even worse (*e.g.* Fig. IV 35, page 209). Unfortunately all figures, including photographs, have been printed on the same paper, which seems to be inadequate for some of the photographic reproductions, *viz.* Figs. XII, 11 p. 530; XIII, 57 p. 627; XIV, 4 p. 643; and others. The minor criticism raised above has no essential bearing on the principal aim of this book, which remains a useful and comprehensive guide for all advanced students and research workers in X-ray Crystallography.

H. JAGODZINSKI

Institut für Kristallographie
und Mineralogie der Universität
München 2
Luisenstrasse 37/II
Germany